## Applicant(s)/Patent Under Reexamination Application/Control No. 10/620,348 BEHFAR ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2823 Hsien-ming Lee

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	Α	US-2001/0016247	08-2001	Matsuura et al.	428/188
X	В	US-6,452,110	09-2002	Clevenger et al.	174/257
	ပ	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			,
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N						
	0						
	Р						
	Q						
	R						
	s						
	Т		·				

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
	x							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.